Compliant with IEC 62474/ D9.00

MICROCHIP Somiconductor Davies Type: SM (C2X) 009 SQLL 200in Massa Time				Termination Base Alloy: Copper Alloy (Cu)			Package Homogeneous Materials: 8.1 Electronics (e.g. pc boards, displays)			
Semiconductor Device Type:	SM	(C3X) 008 SOIJ .208in Matte Tin	% Total					1		e3
Basic Substance	CAS Number	Sub-Component	Weight	mg/part	ppm	99.27	(mg) Total	Mold Compound	% ot Total Weight	79.8
Silica, vitreous	60676-86-0	Mold Compound	69.354	86.277	693,542		Silica, vitreous	60676-86-0	86.91	
Epoxy Resin	Trade Secret	Mold Compound	6.121	7.614	61,207		Epoxy Resin	Trade Secret	7.67	
Phenolic Resin	Trade Secret	Mold Compound	4.078	5.073	40,778		Phenolic Resin	Trade Secret	5.11	
Carbon Black	1333-86-4	Mold Compound	0.247	0.308	2,474		Carbon Black	1333-86-4	0.31]
Copper	7440-50-8	Lead Frame	10.031	12.479	100,314			Total	100.00	
Iron	7439-89-6	Lead Frame	0.247	0.307	2,468	13.06	(mg) Total	Lead Frame	% of Total Weight	10.5
Silver	7440-22-4	Lead Frame	0.200	0.249	2,000		Copper	7440-50-8	95.54	
Zinc	7440-66-6	Lead Frame	0.013	0.016	131		Iron	7439-89-6	2.35	
Phosphorous	7723-14-0	Lead Frame	0.009	0.011	87		Silver	7440-22-4	1.91	
Silver (Ag)	7440-22-4	Die Attach	0.563	0.700	5,625		Zinc	7440-66-6	0.13	
Modified Epoxy Resin	13561-08-5	Die Attach	0.105	0.131	1,050		Phosphorous	7723-14-0	0.08	<u> </u>
Diglycidylether of bisphenol-F	54208-63-8	Die Attach	0.056	0.070	563			Total	100.00	
Modified Amine	827-43-0	Die Attach	0.026	0.033	263	0.93	(mg) Total	Die Attach	% of Total Weight	0.75
Silicon	7440-21-3	Chip (Die)	7.500	9.330	75,000		Silver (Ag)	7440-22-4	75.00	
Copper	7440-50-8	Wire Bond palladium coated copper (CuPd)	0.197	0.244	1,965		Modified Epoxy Resin	13561-08-5	14.00	l
Palladium	7440-05-3	Wire Bond palladium coated copper (CuPd)	0.004	0.004	35	D	iglycidylether of bisphenol-F		7.50	1
Tin	7440-31-5	Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1 hour	1.250	1.555	12,500		Modified Amine	827-43-0	3.50	<u> </u>
TOTALS: 100.000 124.400 1,000,000							Total	100.00		
0.1244 g Total Mass					9.33	Total (mg)	Chip (Die)	% of Total Weight	7.5	
s semiconductor device and its homogenous materials comply w 5) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption		: 2002/95/EC (27 January 2003) & Directive 2011/65/EU (08	June 2011) ar	nd 2015/863/El	J (31 March					
-, (()	(2010)						Doped Silicon	7440-21-3	100.00	
empliance with the above EU Directives has been verified via interior		ls, supplier declarations, and /or analytical test data.					Doped Silicon	7440-21-3 Total	100.00]
mpliance with the above EU Directives has been verified via internance with the above EU Directives has been verified via internance chemical substance is absent from the list above, the chemical sorporated's knowledge and belief as of the date of this document	nal design contro ubstance is NOT , there is no credi	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concer				0.25	(mg) Total			
mpliance with the above EU Directives has been verified via interi chemical substance is absent from the list above, the chemical s orporated's knowledge and belief as of the date of this document, is not below the threshold of regulatory concern for any regulat lding compounds used by Microchip meet the UL94 V0 flammabil	nal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concer 1-wide.	tration of the	chemical subs		0.25	<u> </u>	Total Wire Bond - Copper, palladium	100.00	
	nal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concersi-wide. Lastics. You can access the UL iQTM family of databases to	ntration of the	chemical subs	stance, if	0.25	(mg) Total	Total Wire Bond - Copper, palladium coated (CuPd)	100.00 % of Total Weight	
impliance with the above EU Directives has been verified via internal chemical substance is absent from the list above, the chemical storporated's knowledge and belief as of the date of this document y, is not below the threshold of regulatory concern for any regulated in the compounds used by Microchip meet the UL94 V0 flammabil p://ul.com/global/eng/pages/offerings/industries/chemicals/plastic e protective "tubes" in which the specific product is shipped are retain "reels" may be made from PVC plastic.	nal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p ss/ nade from polyvi	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concert-wide. lastics. You can access the UL iQTM family of databases to any chloride (PVC) plastic. "Window envelopes" used to ho	ntration of the	chemical subs	stance, if	0.25	(mg) Total Copper	Total Wire Bond - Copper, palladium coated (CuPd) 7440-50-8	100.00 % of Total Weight 98.25	
impliance with the above EU Directives has been verified via internal chemical substance is absent from the list above, the chemical storporated's knowledge and belief as of the date of this document y, is not below the threshold of regulatory concern for any regulated by the compounds used by Microchip meet the UL94 V0 flammabil p://ul.com/global/eng/pages/offerings/industries/chemicals/plastic e protective "tubes" in which the specific product is shipped are resulted.	anal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p ss/ made from polyvi form concerning mowledge and be compiled based , some information the average weig	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concert-wide. lastics. You can access the UL iQTM family of databases to a lastics. You can access the UL iQTM family of databases to a lastics. You can access the UL iQTM family of databases to a lastic in the control of th	ntration of the obtain a test obtain a test old the packing accorporated's y Incorporated dy raw mund raw materi	report at slip on the or semiconducto d cannot guara taterial supplie al suppliers. It	stance, if uter box and or devices in antee the ers. Supplier nformation is	0.25	(mg) Total Copper	Total Wire Bond - Copper, palladium coated (CuPd) 7440-50-8	100.00 % of Total Weight 98.25 1.75	
impliance with the above EU Directives has been verified via interial chemical substance is absent from the list above, the chemical storporated's knowledge and belief as of the date of this document y, is not below the threshold of regulatory concern for any regulation of the compounds used by Microchip meet the UL94 V0 flammability/lul.com/global/eng/pages/offerings/industries/chemicals/plastic e protective "tubes" in which the specific product is shipped are retain "reels" may be made from PVC plastic. Crochip Technology Incorporated believes the information in this ieir original packing materials is true and correct to the best of its impleteness and accuracy of data in this form because it has been ormation is often protected from disclosure as trade secrets and sovided only as estimates of the average weight of these parts and	anal design contro ubstance is NOT, there is no credi ory scheme work ity standard for p ss/ made from polyvi form concerning mowledge and be compiled based of some information the average weig devices (silicon	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concert-wide. lastics. You can access the UL iQTM family of databases to a lastics. You can access the UL iQTM family of databases to a lastics. You can access the UL iQTM family of databases to a lastic in the lastic in this form. Microchip Technology In the ranges provided in Material Safety Data Sheets provided in Material Safety Data Sheets provided by subcontract assemblers a ht of anticipated significant toxic metals components. The IC) in the finished parts. d, with respect to the information provided in this declaration.	ntration of the obtain a test obtain a test old the packing acorporated's a y Incorporated ided by raw materise estimates of the control of t	report at I slip on the out semiconducto d cannot guara aterial supplie al suppliers. It o not include sive, limited p	stance, if uter box and or devices in antee the ers. Supplier frormation is trace levels	0.25	(mg) Total Copper	Total Wire Bond - Copper, palladium coated (CuPd) 7440-50-8	100.00 % of Total Weight 98.25 1.75	0.2
mpliance with the above EU Directives has been verified via interic chemical substance is absent from the list above, the chemical storporated's knowledge and belief as of the date of this document y, is not below the threshold of regulatory concern for any regulat Idding compounds used by Microchip meet the UL94 V0 flammabil p://ul.com/global/eng/pages/offerings/industries/chemicals/plastic e protective "tubes" in which the specific product is shipped are retain "reels" may be made from PVC plastic. Crochip Technology Incorporated believes the information in this irroriginal packing materials is true and correct to the best of its impleteness and accuracy of data in this form because it has been ormation is often protected from disclosure as trade secrets and adopants, metals, and non-metal materials contained within silicon crochip Technology Incorporated does not provide any warranty, rranties provided by Microchip Technology Incorporated and its s	anal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p ss/ made from polyvi form concerning knowledge and be compiled based some information the average weig devices (silicon express or implie subsidiaries are conto	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concert-wide. lastics. You can access the UL iQTM family of databases to a lastics. You can access the UL iQTM family of databases to a lastics. You can access the UL iQTM family of databases to a lastic the lastic through through the lastic through through the lastic through the lastic through through the lastic through through the lastic through through the lastic through throug	o obtain a test of the packing accorporated's y incorporated ided by raw m and raw materi se estimates d ion. The exclu acle. These are	report at y slip on the or semiconducto d cannot guaraterial supplie al suppliers. In lo not include sive, limited p provided in N , consequentia	uter box and or devices in antee the ers. Supplier afformation is trace levels roduct flicrochip's		(mg) Total Copper Palladium	Total Wire Bond - Copper, palladium coated (CuPd) 7440-50-8 7440-05-3 Total Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1	98.25 1.75	0.2
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